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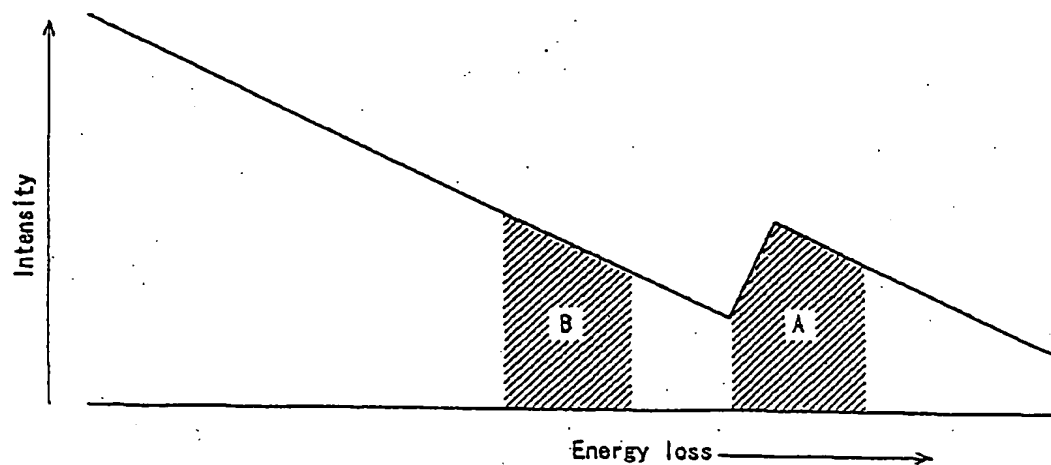
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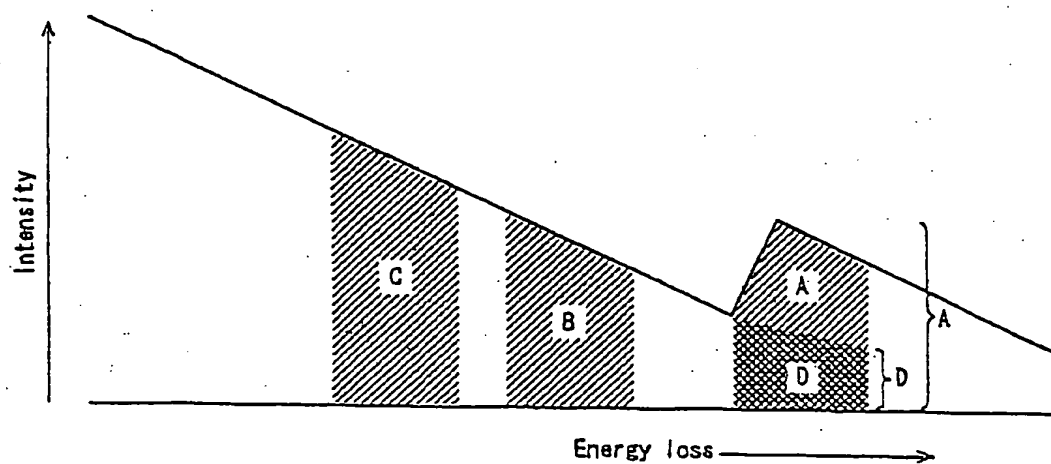
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Fig. 1



Prior Art

Fig. 2



Prior Art

Fig. 3

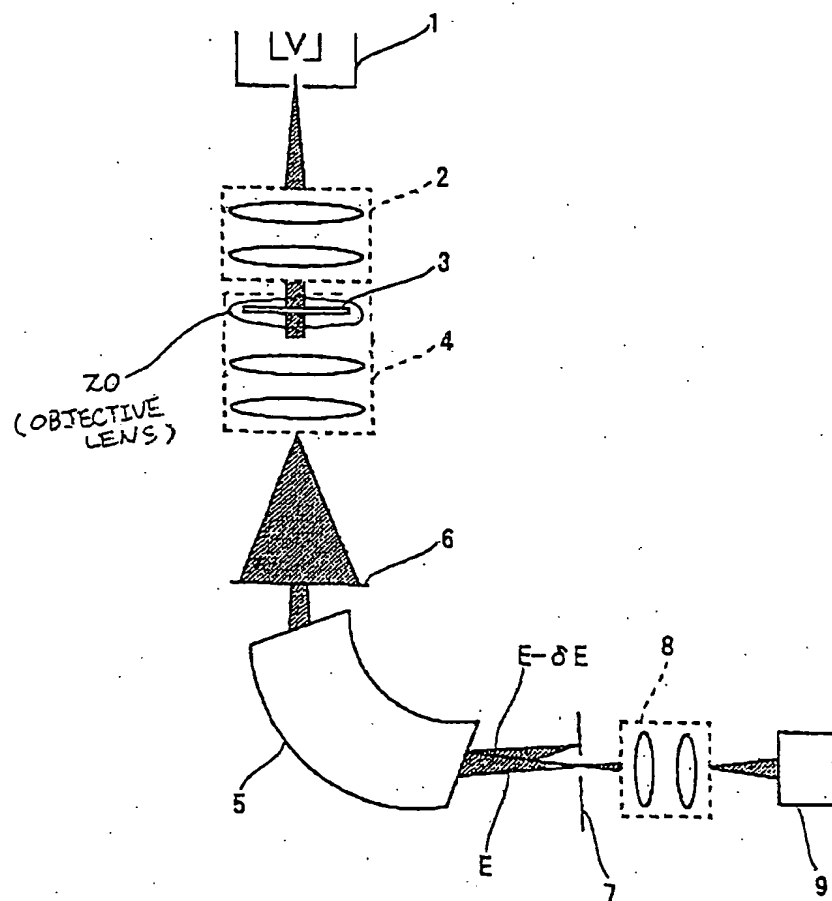


Fig. 4

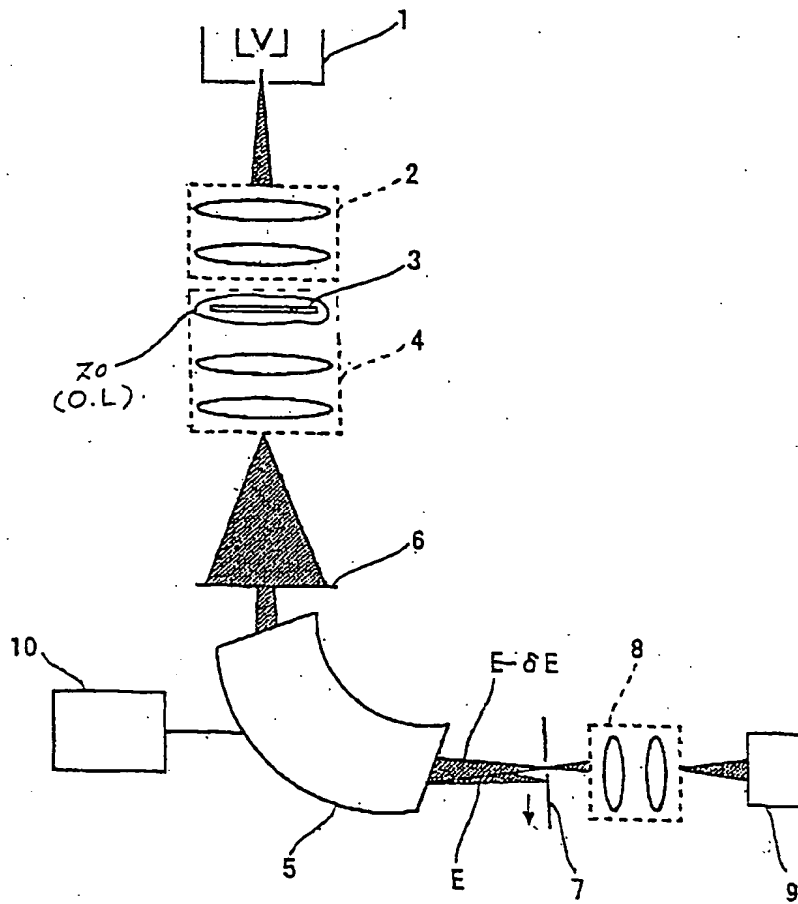


Fig. 5

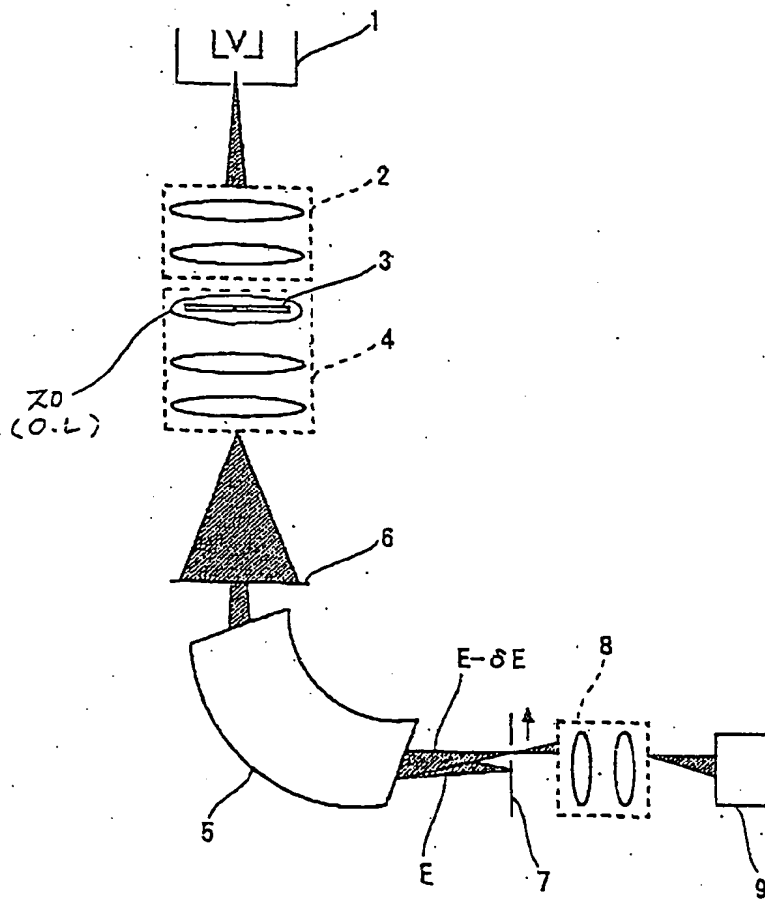


Fig. 6

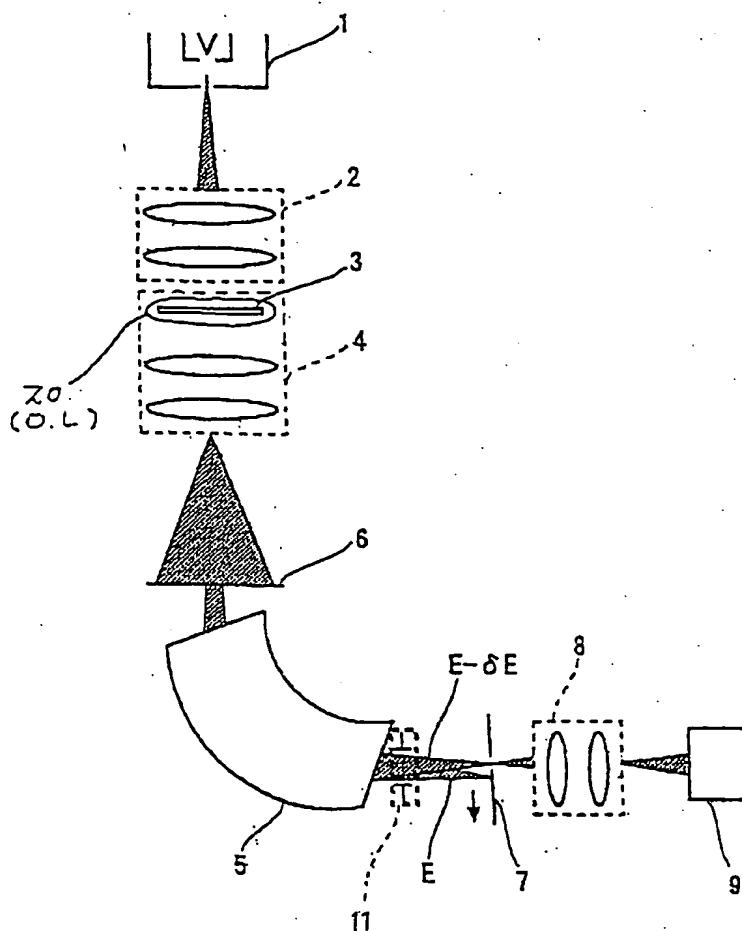
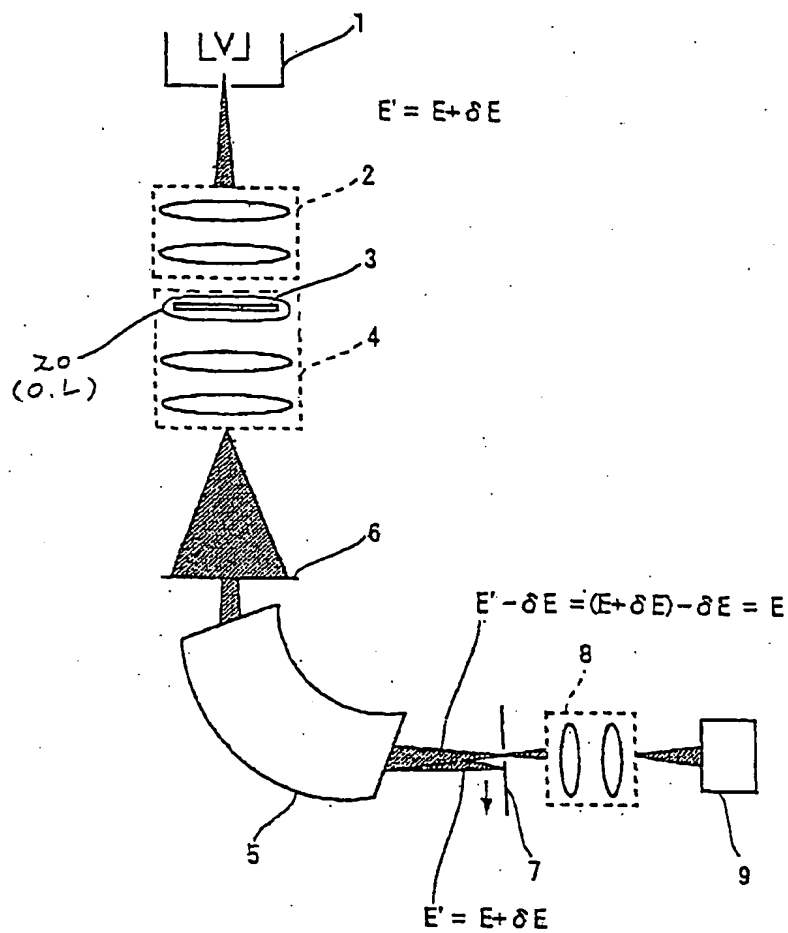


Fig. 7



"Electron Beam Apparatus Having Electron Analyzer and Method of Controlling Lenses"

Inventor: Toshikatsu KANEYAMA

Attorney Docket No. 116-040128

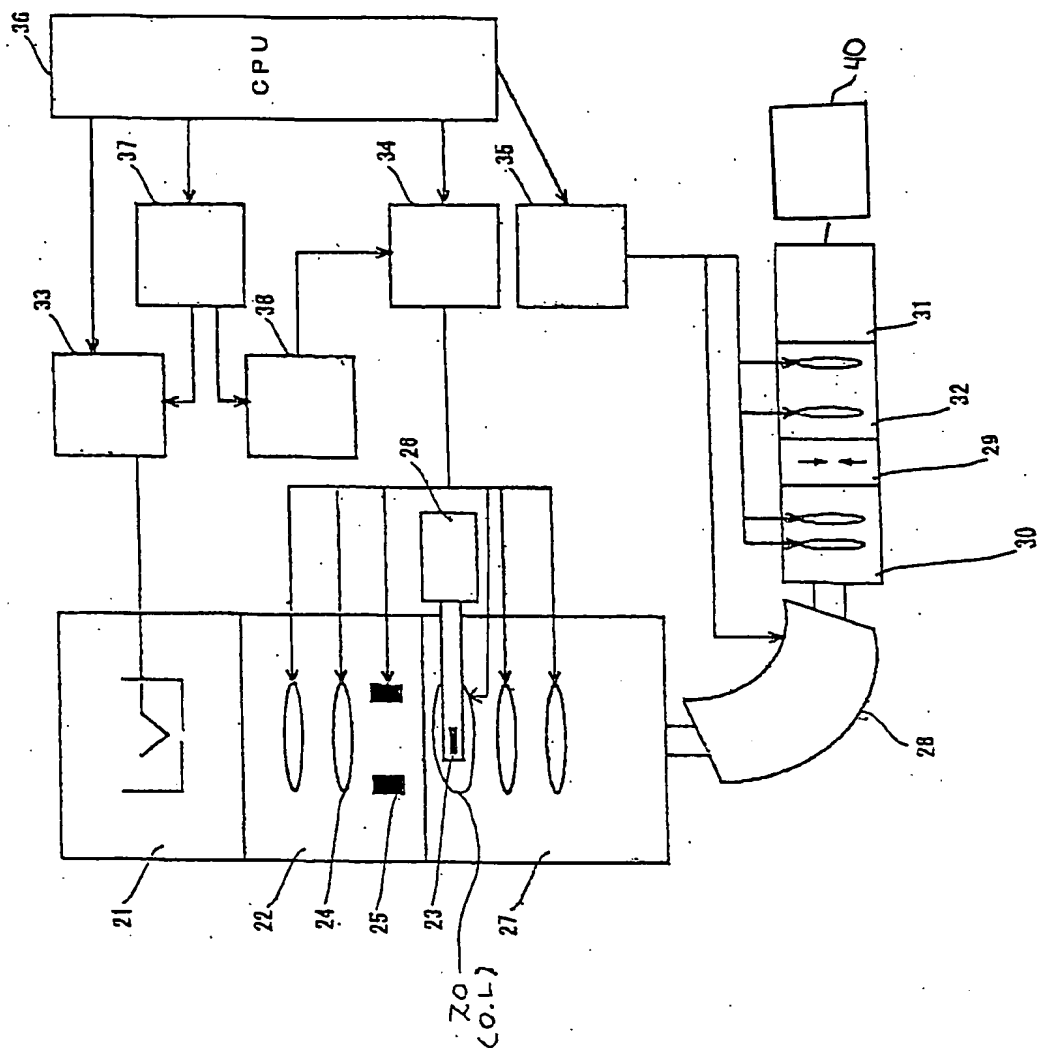


Fig. 8